

**Search Notes**

Application/Control No.

10/520,077

Examiner

Hieu P. Nguyen

Applicant(s)/Patent under  
Reexamination

UEDA ET AL.

Art Unit

2817

**SEARCHED**

Class	Subclass	Date	Examiner
330	295	5/23/2006	HN
330	310	5/23/2006	HN
330	124r	5/23/2006	HN
330	307	5/23/2006	HN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
MOTTOLA STEVEN J	5/23/2006	HN